1.1. Content

This specification covers the performance requirements for the AMP* standard keyboard switch assembly. These switch assemblies are designed to be mounted on printed circuit boards for use in devices where momentary switching is needed.

1.2. Qualification

When tests are performed on the subject product line, the procedures specified in AMP 109 series specifications shall be used. All inspections shall be performed using the applicable QIP and product drawing.

2. APPLICABLE DOCUMENTS

The following documents form a part of this specification to the extent specified herein. In the event of conflict between the requirements of this specification and the product drawing, the product drawing shall take precedence. In the event of conflict between the requirements of this specification and the referenced documents, this specification shall take precedence.

2.1. AMP Specifications

- A. 109-1: General Requirements for Test Specifications
- B. 109 Series: Test Specifications as indicated in Figure 1.

(Comply with MIL-STD-202, MIL-STD-1344 and EIA

RS-364)

C. 114-2014: Switch, Keyboard, Application of

3. REQUIREMENTS

3.1. Design and Construction

Switch assemblies shall be of the design, construction, and physical dimensions specified on the applicable product drawing.

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3.2. Materials

- A. Leaf Spring, PN 62312, 62353, 62477, 62815 and 520067:
 302 stainless steel, temper D, .003 thick, tin plated mounting legs.
- B. Feed-thru-button, PN 62313, 62380, 62476, 62911 and 520066: Nickel silver, temper 2, .006 thick and C 72500, temper 2, .006 thick.

3.3. Performance and Test Description

Switch assemblies shall be designed to meet the electrical, mechanical and environmental performance requirements specified in Figure 1.

3.4. Test Requirements and Procedures Summary

Test Description	Requirement	Procedure
Examination of Product	Meets requirement of product drawing and AMP Spec 114-2014. ELECTRICAL	Visual, dimensional, and functional per QIP.
Contact Resistance,	Measurement Resistance	Mount quitab visials in
Static Closure	Time ohms max Before 1.0 unplate Life 0.1 gold After 3.5 unplated Life 1.0 gold	force displacing apparatus. Deflect switch along centerline using a .100 diameter
Dielectric Withstanding Voltage	Switch shall withstand a test potential of 300 volts, 60 Hz at 85°C for 1 minute without breakdown.	Test between switch terminals and feed through button terminal; AMP Spec 109-29-1.
Dielectric Breakdown	Switch shall withstand 1000 vrms per switch assembly.	Test between switch terminals and feed through button terminal; AMP Spec 109-29-3, except voltage shall be increased at 500 volts/second until failure.

Figure 1 (cont)

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Negation Negative								
No switch closure; no physical damage. 10-60-10 Hz traversed in 5 minutes at .030 total excursion; AMP Spec 109-21-1, procedure only.	Test Description	Red	quire	ment	Procedure			
physical damage. physical damage. in 5 minutes at .030 total excursion; AMP Spec 109-21-1, procedure only.	MECHANICAL							
Life Cycling Contact resistance; contact bounce. Dielectric withstanding voltage; no switch closure; no physical damage. Operating Force Initial: 170-250 grams Final: Overtravel Overtravel Shall be contact adminum/switch; no permanent damage; key downtime; keystroke response. Key Downtime Circuit continuity shall be established within 1.0 millisecond of application of force required to depress switch. Keystroke Response Switch shall be open 100 millisecond maximum after force required to fully depress keyswitch is removed. Switch shall be open 100 milliseconde is removed. Figure 1 (cont) Subject switch to 1,000,000 cycles at 5 cycles/second; AMP Spec 109-20-1. Mount switch in sultable force-displacement measurement apparatus (Instron); deflect switch along centerline using a .100 diameter button through, 016 travel. Record maximum operating force. Continue travel after contact until switch in apparatus necessary to depress switch fully and apply force required to do so for 10 milliseconds; check for continuity. Using an oswitch content button, apply force along switch centerline necessary to fully depress switch (fully depress switc	Vibration	11		•	in 5 minutes at .030 total excursion; AMP			
contact bounce. 1,000,000 cycles at 5 cycles/second; AMP Spec 109-201.		1			procedure only.			
voltage; no switch closure; no physical damage. Operating Force Initial: 170-250 grams Final: Overtravel Initial: 170-250 grams Final: Overtravel Shall be sutch through .016 travel. Record maximum operating force. Overtravel Overtravel shall be .0005 minimum/switch; no permanent damage; key downtime; keystroke response. Key Downtime Circuit continuity shall be established within 1.0 millisecond of application of force required to depress switch fully and apply force required to depress switch fully and apply force required to fully depress keyswitch is removed. Keystroke Response Keystroke Response Switch shall be open 100 millisecond maximum after force required to fully depress keyswitch is removed. Figure 1 (cont) Mount switch in sultable force-displacement measurement apparatus (Instron); deflect switch actuatil switch in sultable force-displacement measurement apparatus (Instron); deflect switch attwail special switch is fully depressed. Mount switch in sultable force-displacement measurement apparatus (Instron); deflect switch attwail special switch is fully depressed. Mount switch in sultable force-displacement measurement apparatus (Instron); deflect switch attwail special	Life Cycling	E I		-	Subject switch to 1,000,000 cycles at 5 cycles/second; AMP Spec 109-2001.			
Operating Force Initial: 170-250 grams Final: Simil	Shock	voltage; closure;	no s	witch	milliseconds maximum; AMP Spec 109-26-7,			
Overtravel Overtravel Overtravel shall be .0005 minimum/switch; no permanent damage; key downtime; keystroke response. Key Downtime Circuit continuity shall be established within 1.0 millisecond of application of force required to depress switch. Switch shall be open 100 milliseconds; check for continuity. Keystroke Response Switch shall be open 100 millisecond maximum after force required to fully depress keyswitch is removed. Switch shall be open 100 milliseconds; check for continuity. Using an oscilloscope and a .100 diameter switch actuator button, apply force along switch centerline necessary to fully depress switch (bottom out) release force instantaneously and measure time necessary for switch to open. Figure 1 (cont)	Operating Force	Initial:		250 grams	Mount switch in suitable force-displacement measurement apparatus (Instron); deflect switch along centerline using a .100 diameter button through .016 travel. Record maxi-			
Key Downtime Circuit continuity shall be established within 1.0 millisecond of application of force required to depress switch. Keystroke Response Switch shall be open 100 millisecond maximum after force required to fully depress keyswitch is removed. Switch shall be open 100 witch actuator button, apply force along switch centerline necessary to fully depress switch (bottom out) release force instantaneously and measure time necessary for switch to open. Figure 1 (cont)	Overtravel	.0005 mi no perm key dow	nimui anent ntime	n/switch; damage;	Continue travel after contact until switch is fully depressed.			
Keystroke Response Switch shall be open 100 millisecond maximum after force required to fully depress keyswitch is removed. Switch shall be open 100 millisecond maximum after force required to fully depress keyswitch is removed. Switch actuator button, apply force along switch centerline necessary to fully depress switch (bottom out) release force instantaneously and measure time necessary for switch to open. Figure 1 (cont)	Key Downtime	Circuit of be estable 1.0 million application required	contir lishe secon on of	d within d of force	apparatus necessary to depress switch fully and apply force required to do so for 10 milliseconds; check			
AND AMP INCORPORATED LOC SHEET NO 108-2010	Keystroke Response	millisecon after for fully dep	nd ma ce re press	aximum equired to	Using an oscilloscope and a .100 diameter switch actuator button, apply force along switch centerline necessary to fully depress switch (bottom out) release force instantaneously and measure time necessary			
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Test Description	Requirement	Procedure
Contact Bounce	l millisecond maximum initial, 5 milliseconds maximum after life test on closure or opening. (Interpreted as full return to closure on opening or opening on closure).	Using a filtered 5 volt dc source and a 1000 ohm series resistance, monitor voltage drop across switch using an oscilloscope. Actuate switch with .100 diameter actuator button. Record worst-case reading for 10 closures and 10 openings on each sample.
	ENVIRONMENTAL	
Temperature Operation	No physical damage; contact resistance; dielectric withstanding voltage.	Mount switch in cycling apparatus, cycle switch at a rate of 10 Hz for 1 hour at 60°C and 1 hour at 60°C.
Thermal Shock	No physical damage; dielectric withstanding voltage.	Subject switch assembly to 25 cycles between -10° and 85°C; AMP Spec 109-22.

Figure 1 (end)

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3.5. Switch Tests and Sequences

		Test G	roup (a)			
Test or Examination	1	2	3	4			
	Test Sequence (b)						
Examination of Product	1	1	1	1			
Contact Resistance, Static Closure	1		2,5	4,10			
Dielectric Withstanding Voltage	2,4	3,5	3,6				
Dielectric Breakdown	5						
Vibration		2					
Life Cycling				8			
Shock		4					
Operating Force				2,9			
Overtravel				3			
Key Downtime				6			
Keystroke Response				7			
Contact Bounce				5,11			
Temperature Operation			4				
Thermal Shock	3						

- (a) See Para 4.1.A.
- (b) Numbers indicate sequence in which tests are performed.

Figure 2

4. QUALITY ASSURANCE PROVISIONS

4.1. Qualification Inspection

A. Sample Selection

Switch assemblies and mating printed circuit boards shall be prepared in accordance with applicable Instruction Sheets. They shall be selected at random from current production. Each Test Group shall consist of 24 switch assemblies, prepared in accordance with AMP Specification 114-2014. Where individual readings are specified, 12 readings shall suffice for qualification.

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B. Test Sequence

Qualification inspection shall be verified by testing samples as specified in Figure 2.

(1) Failures attributed to equipment, test setup, or operator deficiencies shall not disqualify the product. When product failure occurs, corrective action shall be taken and samples resubmitted for qualification.

4.2. Quality Conformance Inspection

The applicable AMP inspection plan will specify the sampling acceptable quality level to be used. Dimensional and functional requirements shall be in accordance with the applicable product drawing and this specification.

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